

FRIDAY 2.9.			
		08:30	Get Together
Session n°6	Talk 11	09:00	On demand spatially controlled fabrication of single photon emitters in Si - <i>G. Hlawacek</i>
	Inv 5	09:25	Magnetic patterning using Ne, Co, and Dy FIB - <i>K. Lenz</i>
	Exi 7	10:00	TOFWERK - fibTOF: The strength of SIMS capabilities on FIB-SEM microscopes
		<b>10:25</b>	<b>COFFEE BREAK</b>
Session n°7	Talk 12	11:00	Positioned generation of luminescence defects in 2D materials by helium ion beams - <i>A. Hötger</i>
	Talk 13	11:25	Fabrication of microstructured devices for grain boundary investigations in unconventional superconductor CeCoIn <sub>5</sub> - <i>S. Mishra</i>
	Talk 14	11:50	Application of FIB-TOF-SIMS for 3D high-resolution chemical characterization of Li-ion solid-state batteries - <i>A. Priebe</i>
	Talk 15	12:15	Investigation of the Interaction of a Ga <sup>+</sup> Focused Ion Beam with Zirconia by Electron Backscatter Diffraction - <i>N. Brachhold</i>
		<b>12:40</b>	<b>CLOSING</b>